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**National  
Institute of  
Standards and  
Technology**

**T**he National Institute of Standards and Technology was established in 1988 by Congress to “assist industry in the development of technology . . . needed to improve product quality, to modernize manufacturing processes, to ensure product reliability . . . and to facilitate rapid commercialization . . . of products based on new scientific discoveries.”

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- Scientific Computing Environments<sup>2</sup>
- Computer Services
- Computer Systems and Communications<sup>2</sup>
- Information Systems

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<sup>1</sup>At Boulder, CO 80303.

<sup>2</sup>Some elements at Boulder, CO 80303.

# *Journal of Research of the* **National Institute of Standards and Technology**

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